

Integrated Device Technology, Inc. 2975 Stender Way, Santa Clara, CA - 95054

PRODUCT/PROCESS CHANGE NOTICE (PCN)

PCN #: F0107-02 DATE: 07/15/2001 Product Affected: NW1034, NW6000, NW6001, NW6002	MEANS OF DISTINGUISHING CHANGED DEVICES: Product Mark Back Mark Date Code Other Attachment:: Yes No Samples: Available upon request
DESCRIPTION AND PURPOSE OF CHANGE: Die Technology As a result of Integr Wafer Fabrication Process Semiconductor Corp Assembly Process consist of assembly, for detailed descripti Material Testing At this point, there w Manufacturing Site Data Sheet Devices affected: N Other Packing and orientation.	rated Device Technology, Inc (IDT) acquisition of Newave, USA, there will a consolidation of operations. This will test, backend and packing changes. Please see attachments on of changes. ill be no changes to wafer fab facilities and processes. W1034, NW6000, NW6001, NW6002, NW6003, NW6005, upon request
CUSTOMER ACKNOWLEDGMENT OF RECEIPT: IDT records indicate that you require written notification of this to grant approval or request additional information. If IDT does not will be assumed that this change is acceptable. IDT reserves the right to ship either version manufactured after the on the earlier version has been depleted.	not receive acknowledgement within 30 days of this notice
Customer:	Approval for shipments prior to effective date.
Name/Date: E-	Mail Address:
Title: Ph	one# /Fax# :
CUSTOMER COMMENTS:	
IDT ACKNOWLEDGMENT OF RECEIPT:	
RECD. BY:	DATE:

ATTACHMENT - PCN #: F0107-01

PCN Summary

PCN Type: Assembly, Test, Backend and Packing changes

Commodity NW1034, NW6000, NW6001, NW6002, NW6003, NW6005, NW6006

Forecast or Execute Execute

Planned or Unplanned Planned

Data Sheet Change No Change

Detail of Change See attached

Conversion schedule (Estimated)

15-Oct-01

Sample Availability

Production Shipments

Upon Request

15-Oct-01



Description of Changes

This PCN will replace PDN F-01-02 for device NW 6000AS, NW 6001AS and NW 6002CS. These devices will receive continued support by IDT.

The following changes will be implemented on all existing Newave products:

Manufacturing Site Change:

Newave assembly, test and backend facilities will be transferred selectively to IDT ISO 9001 & 9002 certified assembly, test and backend facilities. Please refer to pages 4-8 for details

Packing/Shipping Change:

Existing Newave packing procedures will be replaced by IDT packing procedures. These consist of different units per tray or tube and moisture classification(as in accordance with JEDEC standard J-STD-020). Please refer to pages 4-8 for details.

Top Mark Change:

Newave logo ("NW") will be replaced by IDT logo "IDT". Also, the Newave top mark format will be replaced with IDT top mark format. This consists of mark orientation change on selective packages. Please refer to pages 4-8 for details.

Effective Dates

This applies to all changes mentioned in section "Description of Changes".

Manufacturing Site Change, Packing/Shipping Change:

Effective October 15th, 2001, customers will receive existing Newave products that are assembled, tested, backend processed at either Newave or IDT approved facilities. This includes also changes in the packing and shipping process from Newave to IDT procedures.

Top Mark Change:

Effective October 1st, 2001, for a certain period of time, customers will receive devices with either the Newave or the IDT logo and top mark format. There will be no mixed shipment of top marked units within one shipping carrier unit.

Attachment



Manufacturing Site Change

ASAT, Hong Kong AMKOR Tech, Philippines AMKOR Tech, Buchon, Korea AMKOR Tech, Bupyung, Korea AMKOR Tech, Kwangju, Korea AMKOR Tech, Kwangju, Korea AMKOR Tech, Seoul, Korea

Mark/Test/Backend locations

UNISEM, Malaysia

Top mark date code contains letter

Z

IDT Penang	P
IDT, Philippines	M
Unisem	U
Amkor Tech,Korea	А
ASAT, Hong Kong	X
Amkor Tech, Philippines	D





Device Name		Assembly Location		Test Location		Packing/Shipping	
From NW	To IDT	From	То	From To		From	То
NW1034BQ	821034DN	Caesar/ASAT	ASAT/AMKOR	ASAT	ASAT/IDT-PNG	50/84/Tray	84/Tray
Mark Orientation			Device Top Mark				assification
From	То	F	rom	1	Го	From	То
NW Logo	IDT •	(Assen) NW1034BQ nbly Lot#) /WW	(IDT Logo) 821034DN USSY		N/A	N/A
				Z: Stepping; L	:Mark Location		

Device Name		Assemb	Assembly Location		Test Location		Shipping	
		From	From To From		То	From	То	
NW	6000AS	ATES	AMKOR	NA	NA	100/Tube 98/		
Mark O	rientation	1	Device 1	op Mark		Moisture Cl	assification	
From	То	F	From		То		То	
NW logo	IDT o	(Asser	(NW Logo) NW6000AS (Assembly Lot#) YYWW		(IDT Logo)NW6000AS EXYYWWL		JEDEC Level 1	
		<u> </u>		Z: Stepping; L:	: Mark Location			





Device Name		Assembly Location		Test L	Test Location		Packing/Shipping	
		From	То	From	То	From	То	
NW	6001AS	ATES AMKOR		NA	NA	50/Tube	48/Tube	
Mark O	rientation		Device 7	Гор Mark		Moisture CI	assification	
From	То	F	From To			From	То	
NW logo	IDT O	(NW Logo) NW6001AS (Assembly Lot#) YYWW		-	(IDT Logo) NW6001AS SYYWWL		JEDEC Level 1	
				Z: Stepping; L	: Mark Location			

Device Name		Assemb	Assembly Location		Test Location		Packing/Shipping	
		From	То	From	То	From	То	
NW6	002CS	OSET	Unisem NA NA		32/Tube	31/Tube		
Mark O	rientation	T	Device 1	Top Mark		Moisture C	assification	
From	То	F	From To			From	То	
NW logo	IDT	(Assen	(NW Logo) NW6002CS (Assembly Lot#) YYWW		(IDT Logo) NW6002CS ZYYWWL ssy		JEDEC Level 1	
	•	•		Z: Stepping; L	.: Mark Location		•	





Device Name		Assembly Location		Test Location		Packing/Shipping	
			То	From	То	From	То
NW6003AS		OSET Unisem/AMKOR		N/A	N/A	32/Tube	31/Tube
Mark O	rientation		Device To	op Mark		Moisture Cl	assification
From	То		From	T	То		То
NW logo	IDT o	(NW Logo) NW6003AS (Assembly Lot#) YYWW		(IDT Logo) NW6003AS ESYYWWL		JEDEC Level 3	JEDEC Level 1
				Z: Stepping; L	: Mark Location		

Device Name		Assemi	Assembly Location		Test Location		Shipping
From To				From	То	From	То
NW	6005AS	OSET	Unisem/AMKOR	N/A N/A		38/Tube	37/Tube
Mark O	rientation	T	Device To	op Mark Moisture Classi			assification
From	То		From To		From	То	
NW logo	IDT o	(Asse	(NW Logo) NW6005AS (Assembly Lot#) YYWW		(IDT Logo) NW6005AS USYYWWL #507		JEDEC Level 1
				Z: Stepping; L	_: Mark Location		<u> </u>

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Device Name		Assemi	Assembly Location		Test Location		Packing/Shipping	
		From To		From	То	From	То	
NW6006AS		OSET Unisem/AMKOR		N/A	N/A	38/Tube	37/Tube	
Mark C	Orientation	1	Device To	op Mark		Moisture CI	assification	
From	То	<u> </u>	From	То		From	То	
NW logo	IDT	(Asse	(NW Logo) NW6006AS (Assembly Lot#) YYWW		(IDT Logo) NW6006AS ZYYWWL #507 WSK		JEDEC Level 1	
				Z: Stepping; L	.: Mark Location			